Display and Capabilities

*PDF-4 only
*PDF-4/SIeve+ only

Search Results

- User-selectable display fields
  - Color coded quality marks
  - Formula and nomenclature fields
  - Strongest and longest lines
  - Unit cell data
  - Atomic coordinates flag*
  - And many more…
- All fields can be sorted
- Calculations for all numeric fields (mean, median, and ESD)
- User-defined graphing of most fields (x-y graphs, histograms, and category graphs)

PDF Card

- d-spacing table and graph for fixed slit intensity, variable slit intensity, and integrated* intensity
- Simulated diffraction pattern*
- Formula and nomenclature fields
- Temperature of data collection
- Unit cell data
- Cross referenced atomic coordinates*
- Crystal (Symmetry Allowed) data field
- References table with DOI's (Digital Object Identifiers)
- XML export

Simulated Diffraction Patterns*

- X-ray diffraction, neutron diffraction, and electron diffraction
- Bragg-Brentano or Debye-Scherrer geometry
- Particle size profile function
- 2θ zero correction
- 2θ, Q, d, and 1/d options for x-axis
- Linear, logarithmic, and square root intensity options for y-axis
- JPEG, PNG, and TIF exports

Raw diffraction (PD3) patterns*

Temperature series *

2D structure diagrams

3D molecular structures*

Bond lengths/angles display*

Selected Area Electron Diffraction (SAED) patterns*

- Overlay image for visual comparison and spot indexing

Electron Backscatter Diffraction (EBSD) patterns*

Ring patterns*

- Overlay image for visual comparison
- Option to simulate uniaxial preferred orientation

Total pattern analysis*: Similarity index compares imported experimental data to simulated diffraction patterns

SIeve/SIeve+

- Phase identification plugin
- Automatically import experimental data for all major XRD file types
- Support for importing 2D diffraction (ring) patterns from image files*
- Custom data processing sets for background removal, smoothing, Kα2 stripping, and peak finding
- Semi-quantitative analysis using RIR method*
- "Smart I/Ic Substitution" uses dynamically cross referenced I/Ic values*

ICDD International Centre for Diffraction Data

ISO 9001:2008 QUALITY ASSURED COMPANY CERTAR, 11406.1